

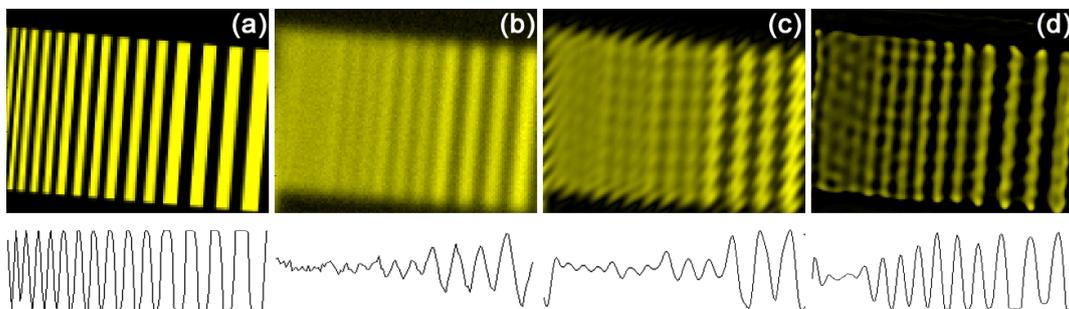
# IMAGE PROCESSING IN SUPER-RESOLUTION TWO-PHOTON POINT-SCANNING STRUCTURED ILLUMINATION MICROSCOPY

Eli Slenders, Martin vandeVen, Marcel Ameloot  
BIOMED, Hasselt University, Agoralaan Bldg C, 3590 Diepenbeek, Belgium  
E-mail : eli.slenders@uhasselt.be

**KEY WORDS:** Structured illumination microscopy, super-resolution imaging, two-photon microscopy, motion artifacts, simulations.

Fluorescence microscopy with a lateral spatial resolution beyond the diffraction limit, i.e. super-resolution microscopy, is of great interest in cell biology. Unlike other super-resolution modalities, structured illumination microscopy (SIM) is fast and does not require a high illumination power. Furthermore, SIM can be made compatible with two-photon fluorescence by point scanning over the sample object with a focused pulsed laser while temporally modulating the excitation intensity, a crucial step for *in vivo* super-resolution microscopy [1].

SIM imaging of living cells is sensitive to motion artifacts [2]. We found lateral mechanical instabilities over 1 to 5 pixels (0.15 – 0.75  $\mu\text{m}$ ) in a Zeiss LSM 510 Axiovert 200M microscope with thermostated enclosure. We simulated the effect of sample stage drift on the SIM reconstruction with grainy, low signal-to-noise ratio fluorescence line patterns. The influence of the illumination modulation depth and the background signal was studied. We compared Tikhonov-Miller (TM, generalized Wiener) filtering [3] and total variation (TV) denoising [4] and show that the “best filter choice” for reconstruction depends on the imaged object spatial information structure.



**Figure 1:** (a) Simulation of a line patterned object, (b) blurred image of the object with Gaussian white noise added to simulate the imaging process, (c) reconstructed image using SIM analysis with TM/generalized Wiener filtering and (d) TV denoising. All images are 320 x 250 pixels. The line plots show the corresponding profile in the images over a horizontal line. A stage drift of 3 pixels horizontally and 3 pixels vertically was assumed between every two scans. A SIM pattern periodicity of 6 pixels was taken, corresponding to the PSF  $1/e^2$  intensity value that was chosen. The SIM reconstruction in this figure was done for 1 angle ( $45^\circ$ ) and 3 phase steps ( $0^\circ$ ,  $120^\circ$ ,  $240^\circ$ ).

- [1] J. J. Field, K. W. Wernsing and S. R. Dominique, “Super-resolved multimodal multiphoton microscopy with spatial frequency-modulated imaging”, *PNAS*, **113**, 6605-6610 (2016).
- [2] R. Förster, K. Wicker, A. Jost, R. Heintzmann, “Motion artefact detection in structured illumination microscopy for live cell imaging”, *Opt. Express*, **24**, 22121-22134 (2016).
- [3] C. H. Righolt, J. A. Slotman, I. T. Young *et al.*, “Image filtering in structured illumination microscopy using the Lukosz bound”, *Opt. Express*, **21**, 24431-24451 (2013).
- [4] K. Chu, P. J. McMillan, Z. J. Smith *et al.*, “Image reconstruction for structured-illumination microscopy with low signal level”, *Opt. Express*, **22**, 8687-8702 (2014).